



SHEET 1 OF 1

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
251148US0SERIAL NO.
10/809,704

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Yuko UCHIMARU, et al.FILING DATE
March 26, 2004

GROUP

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
|---------------------|----|--------------------|------|------|-------|--------------|-------------------------------|
| | AA | | | | | | |
| | AB | | | | | | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |
| | AL | | | | | | |
| | AM | | | | | | |
| | AN | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | TRANSLATION | |
|----|----|--------------------|------------|-------------------------------------|-------------|----|
| | | | | | YES | NO |
| mj | AO | 2002-317049 | 10/31/2002 | JAPAN (with English Abstract) | | X |
| | AP | 2968244 | 08/20/1999 | JAPAN (with English Abstract) | | X |
| | AQ | 3041424 | 03/10/2000 | JAPAN (with translation of claim 1) | | X |
| | AR | 2002-359240 | 12/13/2002 | JAPAN (with English Abstract) | | X |
| mj | AS | 2003-119289 | 04/23/2003 | JAPAN (with English Abstract) | | X |
| | AT | | | | | |
| | AU | | | | | |
| | AV | | | | | |

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

| | | | | | | |
|----|----|--|--|--|--|--|
| mj | AW | International Technology Roadmap for Semiconductors 2002 Update, 2002 Update Tables, page 75, "TABLE 62A MPU INTERCONNECT TECHNOLOGY REQUIREMENTS—NEAR-TERM", 2002 | | | | |
| mj | AX | S. SHINMIYAHARA, et al., Cu-Interconnect Technology, page 227, "LATEST DEVELOPMENT OF CU WIRING TECHNIQUES", (with partial English translation) | | | | |
| | AY | | | | | |
| | AZ | | | | | <input type="checkbox"/> Additional References sheet(s) attached |

Examiner

Michelle J. Janner

Date Considered

6/14/07

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.